

INFORMATION DISCLOSURE CITATION

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Atty. Docket No.	7241-17	Appln. No.	10/049,239
Applicant	Nobuya Kitaguchi et al.		
Filing Date	February 11, 2002	Group:	1743

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate

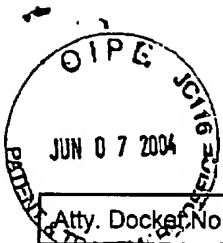
FOREIGN PATENT DOCUMENTS

	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
	2-293640	04/12/90	Japan			No
	4-53384	08/26/92	Japan			No
	8-62225	03/08/96	Japan			No
	10-501340	02/03/98	Japan			No
	09-504732	05/13/97	Japan			No
RX	08233778	09/13/96	Japan			Yes - Abstract
	9-500809	01/28/97	Japan			No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner	Alexander	Date Considered	9/12/04
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NO TRANSLATION OR CHARACTERIZATION	Shuuichi Shouji et al., "Micro Kagaku Bunseki System," Transactions, the Institute of Electronics, Information and Communication Engineers, (Japan), 1998, Vol. J81-C-I, No. 7, pp. 385-393.
	Hiroaki Nakanishi et al., "Micro-fabrication and analytical performances of quartz and glass microchips for electrophoresis," <i>Bunseki Kagaku</i> , Vol. 47, No. 6, pp. 361-368 (1998), <i>The Japan Society for Analytical Chemistry</i>

Examiner	<i>Alexander</i>	Date Considered	<i>1/12/04</i>
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